

# STP36N55M5 STW36N55M5

Datasheet — production data

## N-channel 550 V, 0.06 Ωtyp., 33 A MDmesh<sup>™</sup> V Power MOSFET in TO-220 and TO-247 packages

### Features

Order codes	V <sub>DSS</sub> @ T <sub>Jmax</sub>	R <sub>DS(on)</sub> max	I <sub>D</sub>
STP36N55M5	600 V	< 0.08 Ω	33 A
STW36N55M5	000 V	< 0.00 32	50 A

- Worldwide best R<sub>DS(on)</sub> \* area
- Higher V<sub>DSS</sub> rating and high dv/dt capability
- Excellent switching performance
- 100% avalanche tested

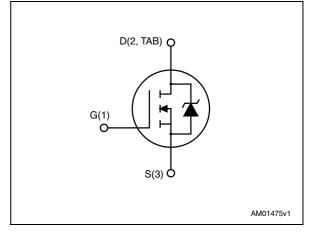
### Applications

Switching applications

### Description

These devices are N-channel MDmesh<sup>™</sup> V Power MOSFETs based on an innovative proprietary vertical process technology, which is combined with STMicroelectronics' well-known PowerMESH<sup>™</sup> horizontal layout structure. The resulting product has extremely low onresistance, which is unmatched among siliconbased Power MOSFETs, making it especially suitable for applications which require superior power density and outstanding efficiency. 

### Figure 1. Internal schematic diagram



### Table 1. Device summary

Order codes	Marking	Package	Packaging
STP36N55M5	36N55M5	TO-220	Tube
STW36N55M5	CINCCINC	TO-247	Tube

#### October 2012

Doc ID 022902 Rev 2

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This is information on a product in full production.

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# 1 Electrical ratings

### Table 2. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V <sub>GS</sub>	Gate-source voltage	± 25	V
Ι <sub>D</sub>	Drain current (continuous) at $T_C = 25 \ ^{\circ}C$	33	А
Ι <sub>D</sub>	Drain current (continuous) at $T_C = 100 \ ^{\circ}C$	20.8	Α
I <sub>DM</sub> <sup>(1)</sup>	Drain current (pulsed)	132	Α
P <sub>TOT</sub>	Total dissipation at $T_C = 25 \ ^{\circ}C$	190	W
dv/dt <sup>(1)</sup>	Peak diode recovery voltage slope	15	V/ns
T <sub>stg</sub>	Storage temperature	- 55 to 150	°C
Тj	Max. operating junction temperature	150	°C

1.  $I_{SD} \leq 33$  A, di/dt  $\leq 400$  A/µs;  $V_{DS(Peak)} < V_{(BR)DSS}$ ,  $V_{DD} = 340$  V.

### Table 3. Thermal data

Symbol	Parameter	Value		Value Unit	
Symbol	Falameter	TO-220	TO-247	Onit	
R <sub>thj-case</sub>	Thermal resistance junction-case max	e max 0.66		°C/W	
R <sub>thj-amb</sub>	Thermal resistance junction-ambient max	62.5 50		°C/W	

### Table 4.Avalanche characteristics

Symbol	Parameter	Value	Unit
I <sub>AR</sub>	Avalanche current, repetetive or not repetetive (pulse width limited by $T_{jmax}$ )	7	А
E <sub>AS</sub>	Single pulse avalanche energy (starting $T_J=25^{\circ}C$ , $I_D=I_{AR}$ ; $V_{DD}=50 V$ )	510	mJ



## 2 Electrical characteristics

(T<sub>C</sub> = 25 °C unless otherwise specified)

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V <sub>(BR)DSS</sub>	Drain-source breakdown voltage	$I_{D} = 1 \text{ mA}, V_{GS} = 0$	550			V
I <sub>DSS</sub>	Zero gate voltage drain current (V <sub>GS</sub> = 0)	V <sub>DS</sub> = 550 V V <sub>DS</sub> = 550 V, T <sub>C</sub> =125 °C			1 100	μΑ μΑ
I <sub>GSS</sub>	Gate-body leakage current (V <sub>DS</sub> = 0)	V <sub>GS</sub> = ± 25 V			± 100	nA
V <sub>GS(th)</sub>	Gate threshold voltage	$V_{DS} = V_{GS}$ , $I_D = 250 \ \mu A$	3	4	5	V
R <sub>DS(on)</sub>	Static drain-source on-resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 16.5 A		0.06	0.08	Ω

#### Table 5. On /off states

### Table 6. Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub>	Input capacitance Output capacitance Reverse transfer capacitance	V <sub>DS</sub> = 100 V, f = 1 MHz, V <sub>GS</sub> = 0	-	2670 75 6.6	-	pF pF pF
C <sub>o(tr)</sub> <sup>(1)</sup>	Equivalent capacitance time related	V <sub>DS</sub> = 0 to 440 V, V <sub>GS</sub> = 0	-	192	-	pF
C <sub>o(er)</sub> <sup>(2)</sup>	Equivalent capacitance energy related	v <sub>DS</sub> = 0 10 440 v, v <sub>GS</sub> = 0	-	71	-	pF
R <sub>G</sub>	Intrinsic gate resistance	f = 1 MHz open drain	-	1.85	-	Ω
Q <sub>g</sub> Q <sub>gs</sub> Q <sub>gd</sub>	Total gate charge Gate-source charge Gate-drain charge	$V_{DD} = 440 \text{ V}, I_D = 16.5 \text{ A},$ $V_{GS} = 10 \text{ V}$ (see <i>Figure 18</i> )	-	62 15 27	-	nC nC nC

1. Time related is defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$ 

2. Energy related is defined as a constant equivalent capacitance giving the same stored energy as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$ 



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Symbol	Parameter	Test conditions	Min.	Тур.	Max	Unit
$\begin{array}{c} t_{d(V)} \\ t_{r(V)} \\ t_{f(i)} \\ t_{c(off)} \end{array}$	Voltage delay time Voltage rise time Current fall time Crossing time	$V_{DD} = 400 \text{ V}, \text{ I}_D = 22 \text{ A},$ $R_G = 4.7 \Omega, V_{GS} = 10 \text{ V}$ (see <i>Figure 19</i> and <i>Figure 22</i> )	-	56 13 13 17	-	ns ns ns ns

Table 7. Switching times

### Table 8.Source drain diode

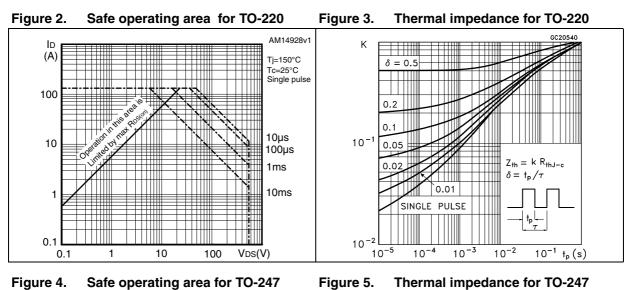
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I <sub>SD</sub> I <sub>SDM</sub> <sup>(1)</sup>	Source-drain current Source-drain current (pulsed)		-		33 132	A A
V <sub>SD</sub> <sup>(2)</sup>	Forward on voltage	I <sub>SD</sub> = 33 A, V <sub>GS</sub> = 0	-		1.5	V
t <sub>rr</sub> Q <sub>rr</sub> I <sub>RRM</sub>	Reverse recovery time Reverse recovery charge Reverse recovery current	I <sub>SD</sub> = 33 A, di/dt = 100 A/µs V <sub>DD</sub> = 100 V (see <i>Figure 22</i> )	-	334 5 31		ns μC Α
t <sub>rr</sub> Q <sub>rr</sub> I <sub>RRM</sub>	Reverse recovery time Reverse recovery charge Reverse recovery current	I <sub>SD</sub> = 33 A, di/dt = 100 A/μs V <sub>DD</sub> = 100 V, T <sub>j</sub> = 150 °C (see <i>Figure 22</i> )	-	406 7 35		ns μC Α

1. Pulse width limited by safe operating area.

2. Pulsed: pulse duration = 300  $\mu$ s, duty cycle 1.5%



### 2.1 Electrical characteristics (curves)



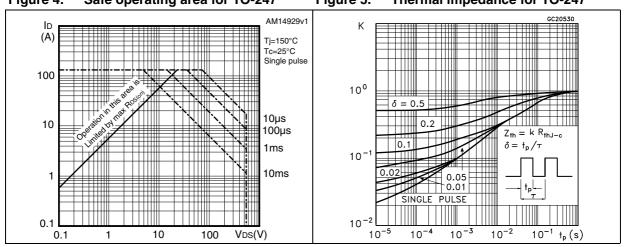
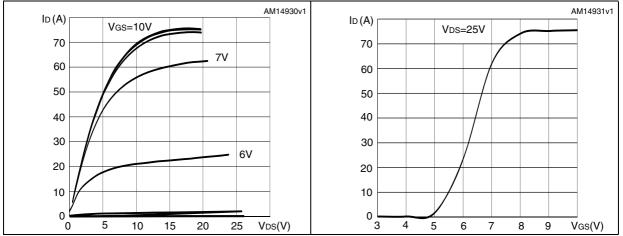




Figure 7. Transfer characteristics





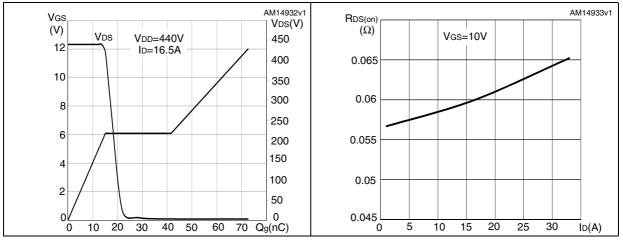
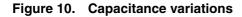


Figure 8. Gate charge vs gate-source voltage Figure 9. Static drain-source on-resistance





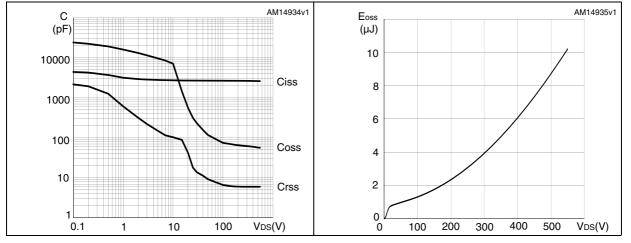
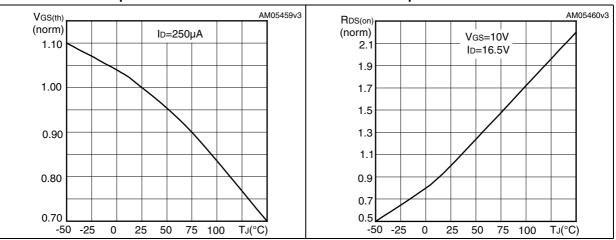


Figure 12. Normalized gate threshold voltage Figure 13. Norm vs temperature temperature

Normalized on-resistance vs temperature





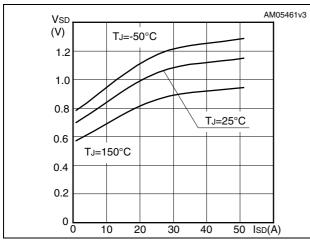
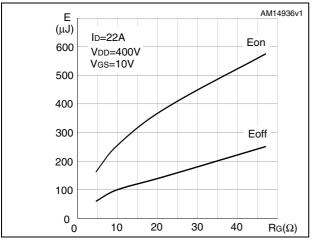


Figure 16. Switching losses vs gate resistance

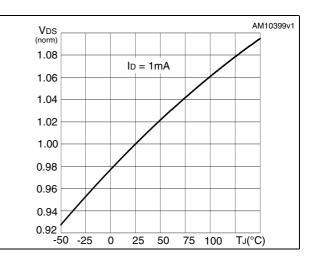


1. Eon including reverse recovery of a SiC diode

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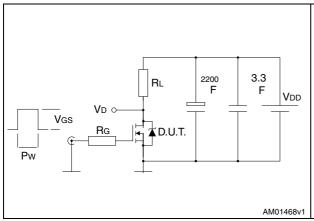
57

### Figure 15. Normalized B<sub>VDSS</sub> vs temperature



## 3 Test circuits

Figure 17. Switching times test circuit for resistive load



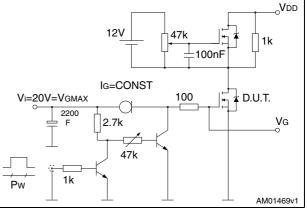
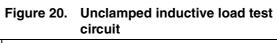


Figure 18. Gate charge test circuit

Figure 19. Test circuit for inductive load switching and diode recovery times



I

J

D.U.T.

2200

F

3.3

F

Vdd

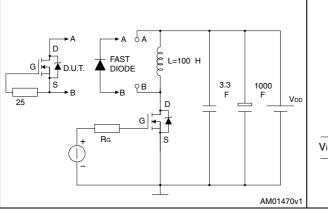
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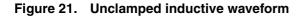
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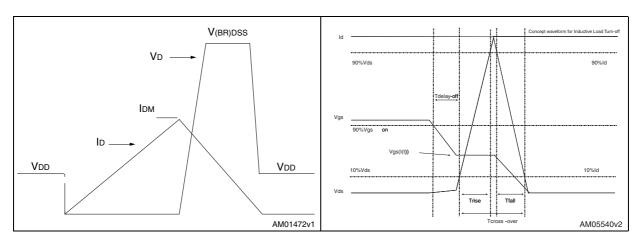
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## 4 Package mechanical data

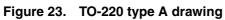
In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK<sup>®</sup> packages, depending on their level of environmental compliance. ECOPACK<sup>®</sup> specifications, grade definitions and product status are available at: *www.st.com.* ECOPACK is an ST trademark.

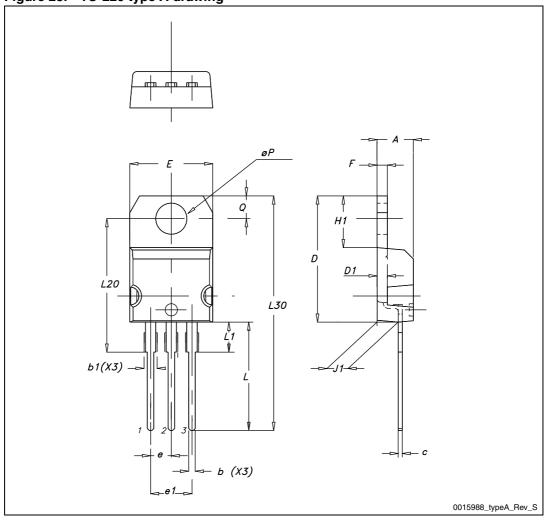
Dim		mm	
Dim. —	Min.	Тур.	Max.
А	4.40		4.60
b	0.61		0.88
b1	1.14		1.70
с	0.48		0.70
D	15.25		15.75
D1		1.27	
E	10		10.40
е	2.40		2.70
e1	4.95		5.15
F	1.23		1.32
H1	6.20		6.60
J1	2.40		2.72
L	13		14
L1	3.50		3.93
L20		16.40	
L30		28.90	
ØР	3.75		3.85
Q	2.65		2.95

Table 9.TO-220 type A mechanical data











Dim		mm.	
Dim.	Min.	Тур.	Max.
А	4.85		5.15
A1	2.20		2.60
b	1.0		1.40
b1	2.0		2.40
b2	3.0		3.40
С	0.40		0.80
D	19.85		20.15
E	15.45		15.75
е	5.30	5.45	5.60
L	14.20		14.80
L1	3.70		4.30
L2		18.50	
ØP	3.55		3.65
ØR	4.50		5.50
S	5.30	5.50	5.70

Table 10.TO-247 mechanical data

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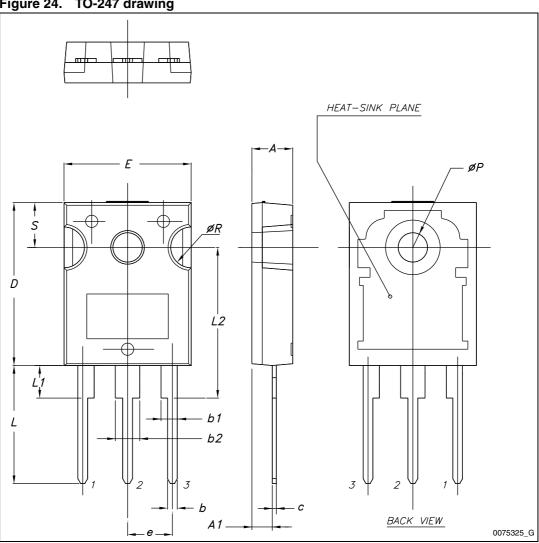


Figure 24. TO-247 drawing



# 5 Revision history

### Table 11.Document revision history

Date	Revision	Changes
07-Mar-2012	1	First release.
23-Oct-2012	2	Document status promoted from preliminary data to production data.



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